

NX2530RH GaN TRANSISTOR

Document Number: NX2530RH
Preliminary Datasheet V2.1

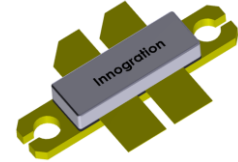
Gallium Nitride 28V 300W, RF Power Transistor

Description

The NX2530RH is a 300W 28V, GaN HEMT, designed for multiple applications with frequencies up to 2.5GHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

NX2530RH



- Typical broadband performance (on Innogrator wideband fixture with device soldered)

V

NX2530RH VGS=-2.50V VDS=28V IDQ=400mA CW								
Freq (MHz)	Psat (dBm)	Psat (W)	IDS (A)	Pin (dBm)	Gain (dB)	Eff (%)	2nd (dBc)	3rd (dBc)
30	52.54	179.5	9.28	38.21	14.33	69.07	-30.80	-10.00
50	52.61	182.4	9.28	38.40	14.21	70.19	-39.50	-10.40
80	53.18	208.0	10.04	33.85	19.33	73.98	-46.00	-11.20
100	53.62	230.1	10.41	37.95	15.67	78.96	-33.70	-11.70
200	53.73	236.0	12.12	35.90	17.83	69.56	-41.60	-12.30
300	53.83	241.5	13.48	36.34	17.49	64.00	-39.10	-13.40
400	53.32	214.8	13.36	36.95	16.37	57.42	-28.10	-11.70
500	53.34	215.8	13.45	37.41	15.93	57.30	-41.80	-11.20
600	53.39	218.3	12.37	36.72	16.67	63.02	-37.20	-18.60
700	53.28	212.8	12.23	36.40	16.88	62.15	-33.10	-21.30
800	53.51	224.4	13.80	37.83	15.68	58.07	-36.70	-26.30
900	53.41	219.3	14.88	38.13	15.28	52.63	-34.50	-35.30
1000	53.58	228.0	14.59	38.34	15.24	55.82	-35.00	-38.00
1100	53.37	217.3	13.30	38.05	15.32	58.34	-41.70	-35.10
1200	53.16	207.0	12.69	39.70	13.46	58.26	-46.10	-30.20
1250	53.15	206.5	12.95	40.50	12.65	56.96	-51.60	-36.20

Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

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Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (28V)
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Table 1. Maximum Ratings (Not simultaneous, TC = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain--Source Voltage	V _{DSS}	150	Vdc
Gate--Source Voltage	V _{GS}	-10,+2	Vdc
Operating Voltage	V _{DD}	40	Vdc
Maximum Forward Gate Current	I _{gmax}	72	mA
Storage Temperature Range	T _{stg}	-65 to +150	°C
Case Operating Temperature	T _c	+150	°C
Operating Junction Temperature(See note 1)	T _j	+225	°C

1. Continuous operation at maximum junction temperature will affect MTTF
2. Bias Conditions should also satisfy the following expression: $P_{diss} < (T_j - T_c) / R_{JC}$ and $T_c = T_{case}$

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case T _c = 85°C, T _j =200°C, DC Power Dissipation(See note 1)	R _{θJC-DC}	0.6	C/W

R_{θJC-DC} is tested at only DC condition, it is related to the highest thermal resistor value among all test conditions. It might be differently lower in different RF operation conditions like CW signal ,pulsed RF signal etc.

Table 3. Electrical Characteristics (T_c = 25°C unless otherwise noted)

DC Characteristics

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{GS} =-8V; I _{DS} =72mA	V _{DSS}	150			V
Gate Threshold Voltage	V _{DS} = 28V, I _D =72mA	V _{GS(th)}	-4	-	-2	V
Gate Quiescent Voltage	V _{DS} =28V, I _{DS} =200mA, Measured in Functional Test	V _{GS(Q)}		-2.7		V

Functional Tests (In Innogration narrow band Test Fixture, 50 ohm system) : V_{DD} = 28 Vdc, I_{DQ} = 200 mA, f = 1000 MHz, Pulse CW

Characteristic	Symbol	Min	Typ	Max	Unit
Power Gain @ P _{sat}	G _p		16		dB
Drain Efficiency @ P _{sat}	Eff		65		%
Saturated Power	P _{sat}		300		W
Input Return Loss	IRL		-7		dB
Mismatch stress at all phases (Device no damage)	VSWR		10:1		Ψ

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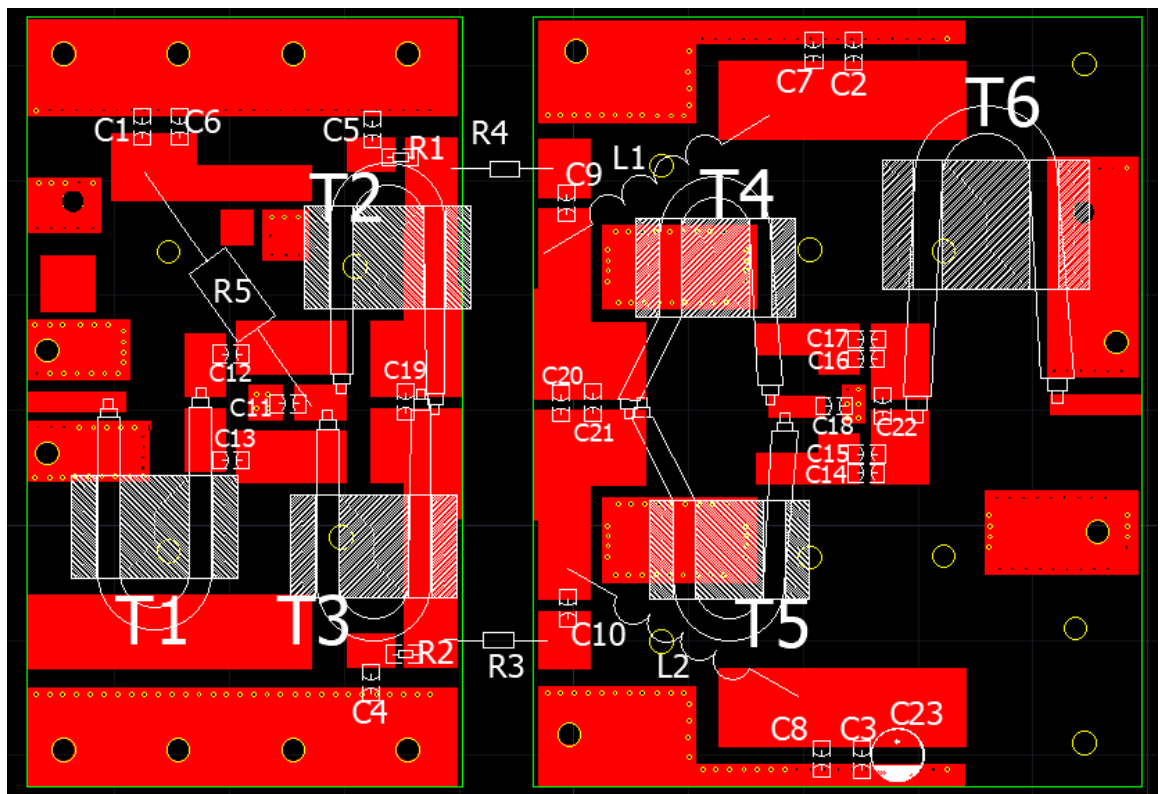
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80-1200MHz

Figure 1: Network analyzer output, S11 and S21



Figure 2: Picture of application board class AB



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Component	Description	Suggestion
C1~C5	10uF/200V-1210	Ceramic multilayer capacitor
C6~C8,C11,C18	820pF	
C9,C10	1000pF	
C12,C13	39pF	
C14~C17	200pF	
C19,C21	10pF	
C20	7.5pF	
C22	0.5pF	
C23	470uF/63V	Electrolytic Capacitor
R1,R2	33 Ω -1206	Chip Resistor
R3,R4	200 Ω	RFT-200
R5	300 Ω	color ring resistor
L1,L2	1.5mm wire , 5mm inner diameter, 5Turns	DIY
T1	50 ohm-60mm, BN-61-202	RFSFBU-086-50;BN-61-202
T2,T3	16.7 ohm-55mm,BN-61-202	SFF-16.7-1.5,BN-61-202
T4,T5	16.7 ohm-70mm,NX0-60	SFF-16.7-1.5,NX0-60
T6	50 ohm-60mm, NX0-60	RFSFBU-086-50,NX0-60

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Package Outline

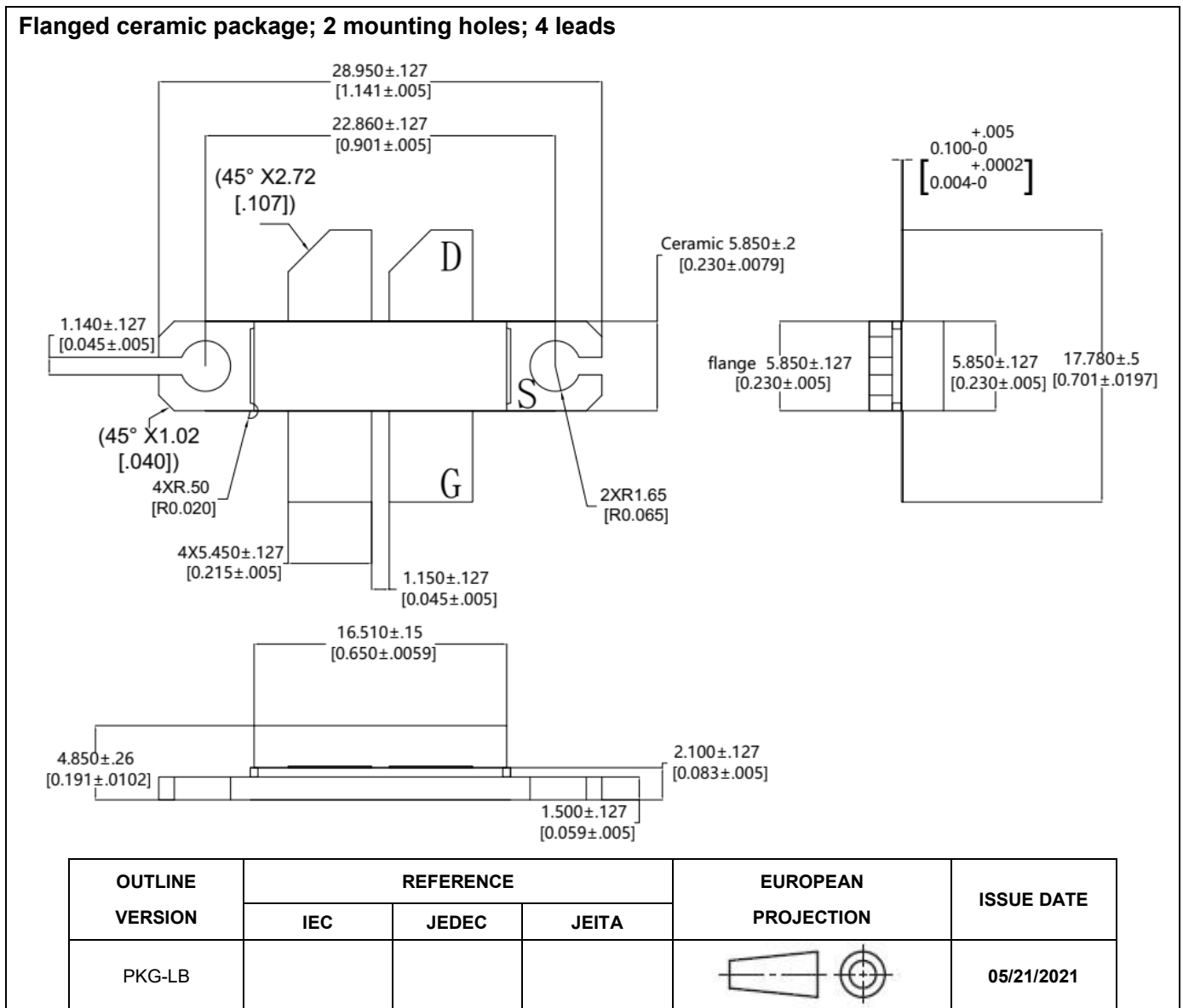


Figure 1. Package Outline PKG-LB(LBB)

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Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2022/5/18	V1.0	Preliminary datasheet creation
2024/6/12	V2.0	Combine NX2530H and NX2530RH and state 2.5GHz supportable
2026/3/20	V2.1	Change the carrier application to 80-1200M 200W new result

Application data based on HL-22-07/TC-26-08

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